Abstracts

A New Measurement Method of the Noise Parameters of Two-Port Devices

N. Fanelli. "A New Measurement Method of the Noise Parameters of Two-Port Devices." 1983 MTT-S International Microwave Symposium Digest 83.1 (1983 [MWSYM]): 366-368.

A new procedure, based on the representation of the noise properties of linear two-ports with uncorrelated noise waves, allows the experimental evaluation of the four noise parameters using only a sliding short as tunable element. Experimental set-up and results obtained from measurements of FET devices are discussed.

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